

ECL SJ-2820 Series

Rev. E

Description

The **SJ-2820 Series** of quartz crystal oscillators provide ECL 10K and 10KH series compatible signals in a ceramic SMD package. Systems designers may now specify space-saving, cost-effective packaged ECL oscillators to meet their timing requirements.

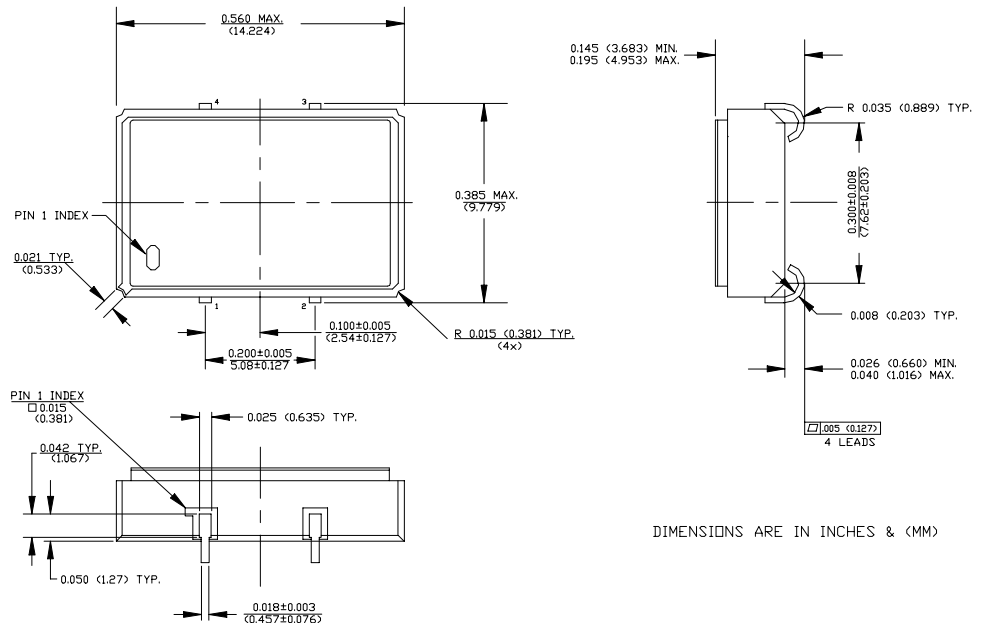
Features

- Wide frequency range—18.0MHz to 250.0MHz
- User specified tolerance available
- Will withstand vapor phase temperatures of 253°C for 4 minutes maximum
- Space-saving alternative to discrete component oscillators
- High shock resistance, to 3000g
- Metal lid electrically connected to ground to reduce EMI
- Low Jitter
- ECL 10K and 10KH series compatible output on Pin 3, complement on Pin 1
- High Q Crystal actively tuned oscillator circuit
- Power supply decoupling internal
- No internal PLL avoids cascading PLL problems
- High frequencies due to proprietary design
- Gold plated leads - Solder dipped leads available upon request

Electrical Connection

Pin Connection

- | | |
|---|-------------------------|
| 1 | Output Complement |
| 2 | V _{CC} /Ground |
| 3 | Output |
| 4 | V _{EE} -4.5V |



SJ-2820 Series Continued
ECL

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Operating Conditions and Output Characteristics

Electrical Characteristics

Parameter	Symbol	Conditions	Min	Typical	Max
Frequency	-----	-----	18.0MHz	-----	250.0MHz
Duty Cycle	-----	@ V_{CC} -1.29V	45/55%	-----	55/45%
Logic 0 ⁽²⁾	V_{OL}	-----	V_{CC} -1.95V	-----	V_{CC} -1.60V
Logic 1 ⁽²⁾	V_{OH}	-----	V_{CC} -1.02V	-----	V_{CC} -0.74V
Rise & Fall Time	tr,tf	20-80% V_O with 50 ohm load to V_{CC} -2V	-----	1.0 ns	1.5 ns
Tpd ⁽⁴⁾	-----	-----	-0.5 ns	-----	+0.5 ns
Jitter, RMS ⁽³⁾	-----	-----	-----	-----	5 psec
Frequency Stability ⁽¹⁾	dF/F	Overall conditions including: voltage, calibration, temp., 10 yr aging, shock, vibration	-100ppm	-----	+100ppm

General Characteristics

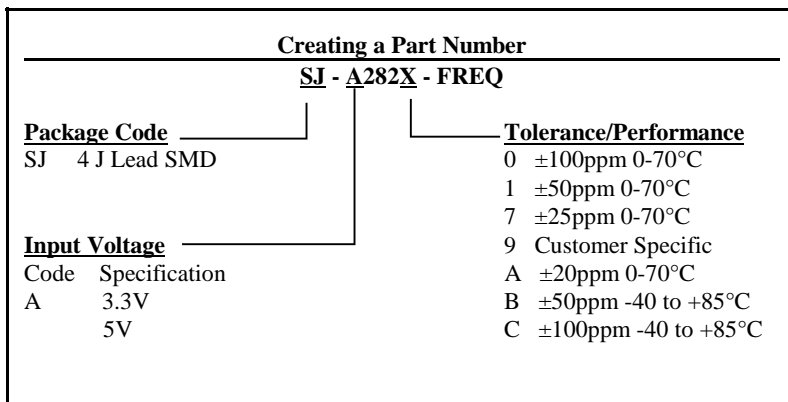
Parameter	Symbol	Conditions	Min	Typical	Max
Supply Voltage	V_{EE}	-----	-4.8V	-4.5V	-4.2V
Supply Current	I_{EE}	50 ohm termination To 2.00V below V_{CC}	0.0 mA	-----	80 mA
Output current	I_O	Low level Output Current	0.0 mA	-----	±50.0 mA
Operating temperature	T_A	-----	0°C	-----	70°C
Storage temperature	T_S	-----	-55°C	-----	125°C
Power Dissipation	P_D	-----	-----	-----	384 mW
Lead temperature	T_L	Soldering, 10 sec.	-----	-----	300°C
Load	50 Ohm to V_{CC} -2V or Thevenin Equivalent, Bias Required	-----	-----	-----	-----
Start-up time	t_s	-----	-----	2 ms	10 ms

Environmental and Mechanical Characteristics

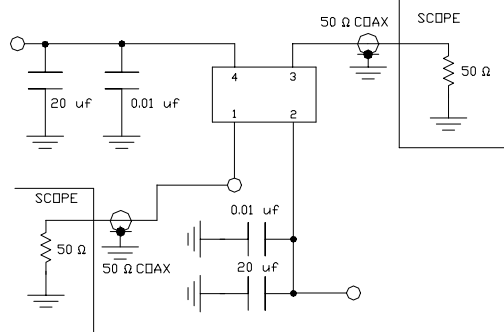
Mechanical Shock	Per MIL-STD-202, Method 213, Condition E
Thermal Shock	Per MIL-STD-833, Method 1011, Condition A
Vibration	0.060" double amplitude 10 Hz to 55 Hz, 35g's 55Hz to 2000 Hz
Soldering Condition	300°C for 10 seconds
Hermetic Seal	Leak rate less than 1×10^{-8} atm.cc/sec of helium
ESD Sensitivity	Human Body Model per ON Semiconductor 10kH series ECL: 500V min.

Footnotes:

- 1) Standard frequency stability ($\pm 20, \pm 25, \pm 50$ ppm & others available)
- 2) V_{OL}, V_{OH} , referenced to ground (V_{CC}) with $V_{EE} = -4.5V$
- 3) Jitter performance is frequency dependent. Please contact factory for full characterization.
- 4) Tpd is phase shift between the falling edge of pin 3 at V_{CC} -1.29V and rising edge of pin 1 at V_{CC} -1.29V.



TEST CIRCUIT



TEST CIRCUIT USES A SPLIT SUPPLY OF +2V AND -2.5V FOR EASE OF TESTING.